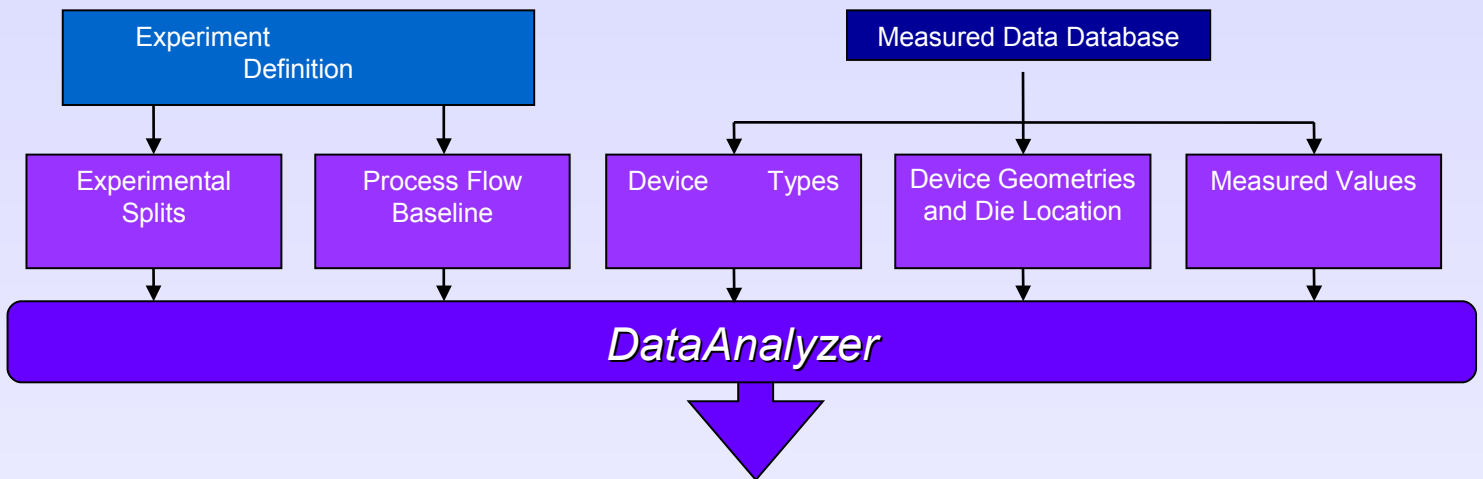


# Stone Pillar DataAnalyzer

## Automated Data Analysis for Process Optimization and Monitoring

**Stone Pillar DataAnalyzer** provides rapid, complete and easy-to-use data analysis, including spreadsheet, scatter plots, box plots, and basic statistics. View data with experimental split information or with timelines of parameter drift. DataAnalyzer makes it simple to quickly traverse from an outlying data point to details of the related experiment, design rules, or test structure layout.

DataAnalyzer includes an automated split lot analysis environment that accelerates lot report generation and speeds learning cycles, squeezing more value from each costly split lot and speeding the process of determining process monitoring or experimental metrics.



Split Number	Die Coord X	Die Coord Y	Wafer Number
1	13	11	1
2	21	21	10
3	4	3	11
4			12
5			13
6			4

Split Number	Die Coord X	Die Coord Y	Wafer Number	ECO Index, Energy, eV	Web Index, Mask, Resolution, nm	Device Type Name	W, UM	L, UM
1	4	3	1	30	5E12	2 Transistor Poly Resistor	3	200
2	13	11	2	25	8E12			
3	21	21	3	30				
4			4					
5			5					
6			6					

**VTX, V**  
 ▲ NLDD Implant, Ene  
 ▲ 20  
 ▲ 25  
 ▲ 30

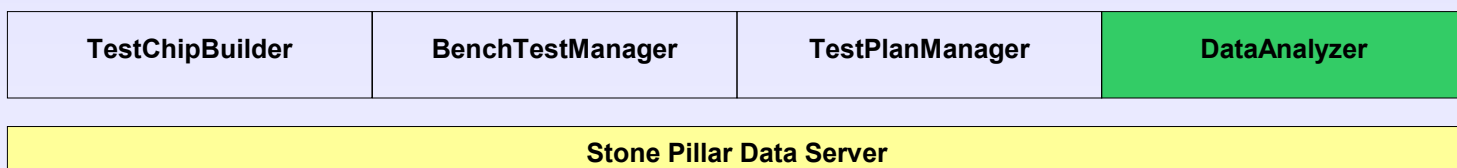
**VTX, V at L, UM = 0.4**  
 N=120 Min=0.458021 Max=0.601488  
 Mean=0.5420403 Median=0.57671297  
 SD=0.057588246

NLDD Implant, Energy, KeV: 20, 25, 30  
 NHalo Implant, Dose, Atoms/cm^2: 5E12, 8E12

Device Type Name: 2 Transistor Poly Resistor  
 W, UM: 3, L, UM: 200

Logged in as spillar@TOSHIBA2003

- Analyze device data by experimental split and by process recipe parameters
- Quickly see basic statistics at the push of a button
- Automatically jump from measured data point to related device target values, experiment, test device layout, test plan, or process flow
- Compare Technology CAD with measured data for rapid calibration
- Optimize device parameters versus design rule parameters
- Analyze data by device geometries and device type
- Compare electrical test data to electrical design rules and performance targets
- Automated data collection
- Automated split lot analysis
- Interactive, multi - variant data analysis
- Automatically generate complete, accurate lot reports
- Integrated box plot, scatter plot, probability plot capability
- Die, wafer, lot, and split level data switches
- Wafer mapping
- Experiment archiving
- Integrated IC layout, test structure, viewer
- Integrated experiment split factor controller



## About Stone Pillar Technologies

Stone Pillar Technologies provides enterprise software solutions for Process & Device Technology Development and Characterization.

*Stone Pillar Suite* is a complete information management system focused on solving problems in semiconductor process & device development.

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